

*We help ideas  
meet the real  
world*



# "Electronic drivers for LEDS - why are many failing ?"

Birger Schneider, DELTA a part of FORCE Technology



Source: Ford Motor Company



- *Concerns about reliability and maintenance of street lighting are not a new phenomena*

# Shortest life component controls the system life



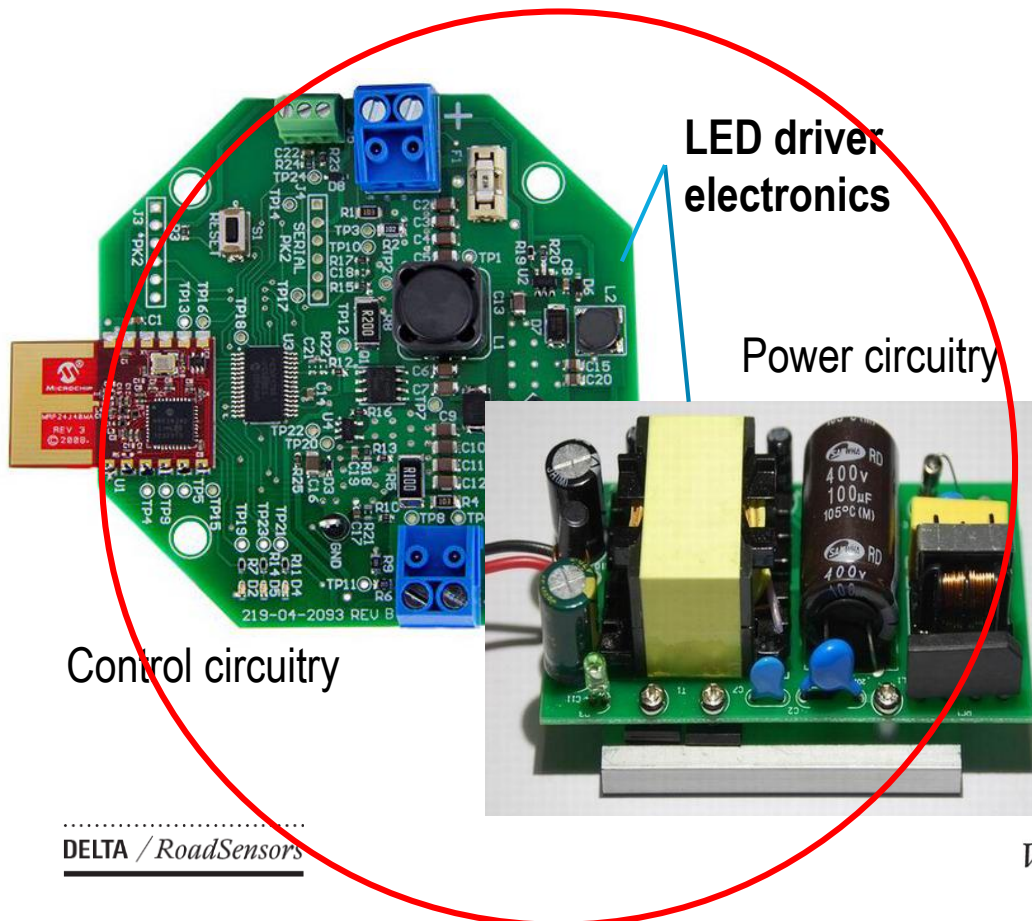
- \* *LED lighting consists of an LED element and an electronic driver in addition to optics, etc..*
- \* *The LED light element itself may have a life timer of >100.000 hours.*
- \* *The electronics of the driver, however, may have a much shorter life.*
- \* ***In any system, it is the element with the shortest life that controls the life of the system.***



# Elements of an LED light source



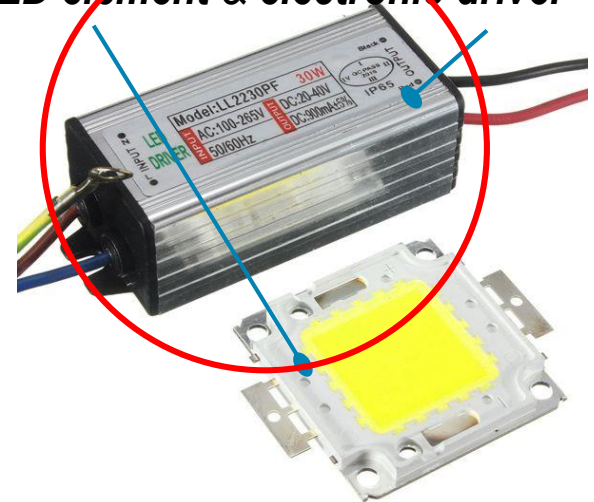
- \* *Primary components of an LED source:*
  - LED diode (chip)
  - LED power driver & control



Integrated LED source



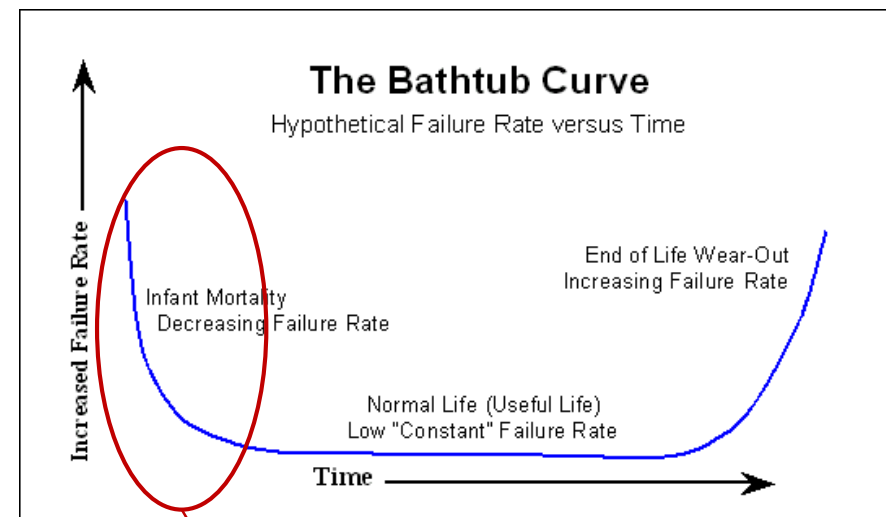
Diskrete LED source incl. separate LED element & electronic driver



# Life cycle



- \* *LED lighting lifetime is basically governed by driver electronics.*
- \* *As such the reliability for LED lighting follows the basic rules of electronics.*
- \* *Some major considerations controls the life of the systems:*
  - **Thermal conditions**
  - **Critical components**
  - **Influence of manufacturing process**
  - **Electrical environment (transients)**

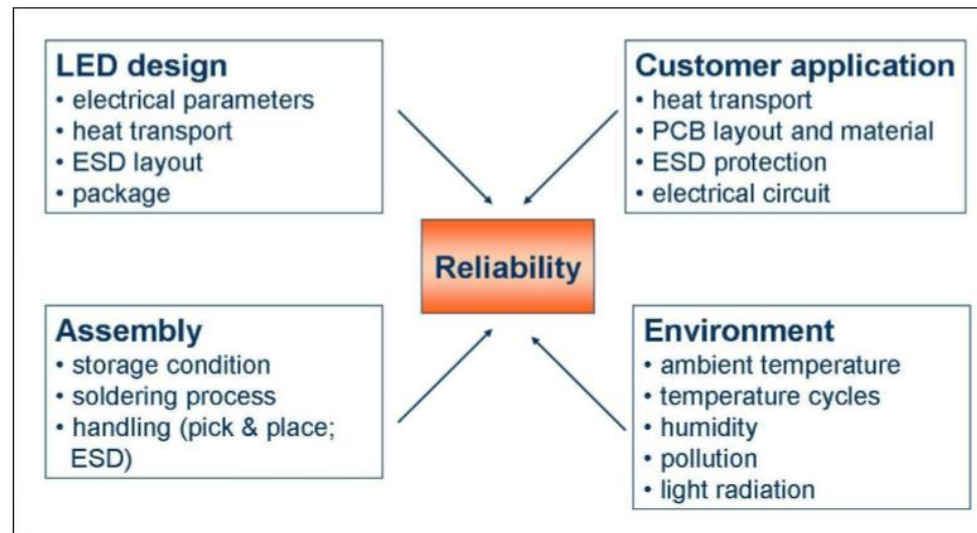


Manufacturing related issues

# Reliability factors



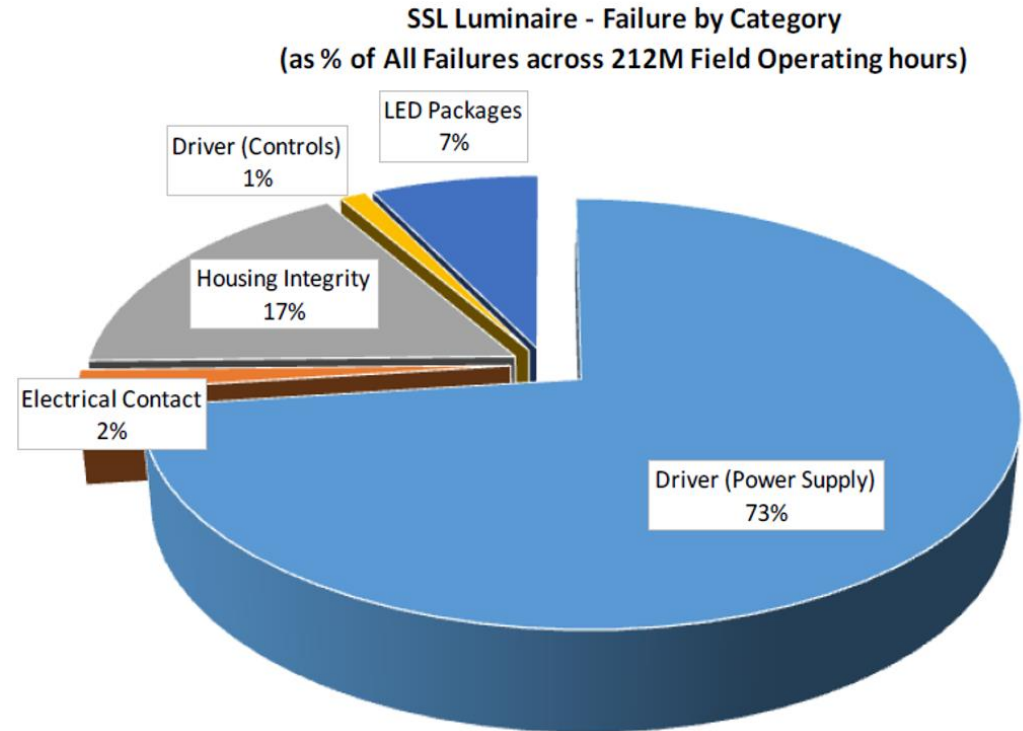
- \* *Reliability of drivers are affected by several factors:*
  - *The design*
  - *The assembly*
  - *The application*
  - *The environment*



# What do users experience (street lighting)?



- \* *A US study by Appalachian Lighting Systems (212 million hours of field use).*
  - *>5% over 7 years*
- \* *A Danish study by ÅF Lighting in 2017 (8 large municipalities & 4 energy suppliers)*
  - *On average >4% failures, 80% of these related to electronic drivers*
  - *5% of luminaries substituted*
  - *2% repaired*



# Causes



- \* *Driver problems may have several causes.*
- \* *Some typical causes are related to:*
  - *Thermal effects*
  - *Critical components*
  - *The electrical environment*





# Thermal Effects

# Limiting thermal conditions

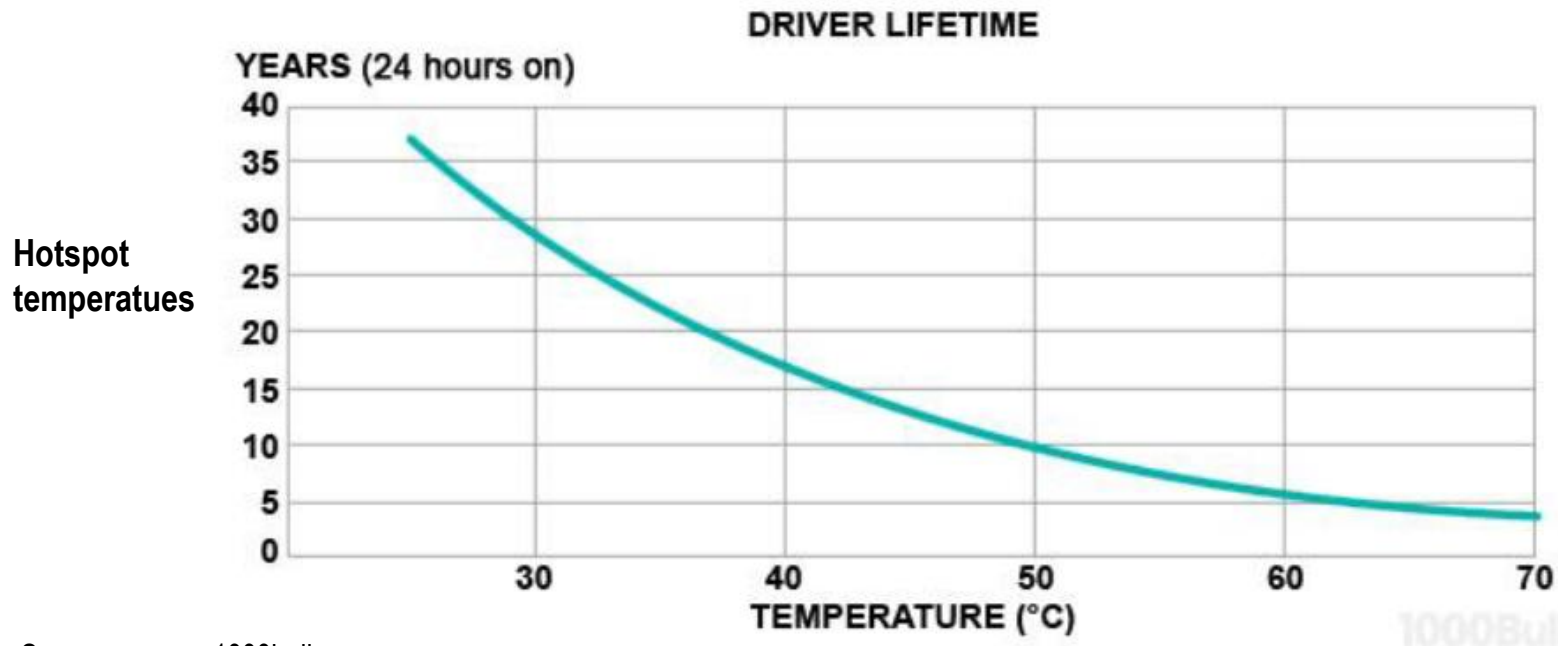


- **High temperatures** (*junction temperatures are critical to electronics components*).
  - *Junction temperature depends on:*
    - *Input power*
    - *Heat removal*
      - *Junction to case*
      - *Case to ambient*
  
- **Temperature cycling** *may often be critical (creates mechanical tension in components)*
  - *Stress depends on:*
    - *Type of component*
    - *Temperature extremes ( $T_{min}$ ,  $T_{max}$ )*
    - *Rate of change of temperature*
    - *Potting*
    - *Others*

# Estimations of life at elevated temperatures



- \* *If a driver is used at a temperature close to its limiting temperature "TC point", it will have a shorter lifespan than if it were operated at a lower temperature.*
- \* *A high TC point will ensure a longer life than drivers with a low TC point.*



Source: 1000bulbs.com  
"Understanding LED drivers"

# Some typical Mfr. guarantees



- \* *Many electronics drivers come with fine lifetime estimations – but reality sometimes is often cruel.*
- \* *According to Illuminating Engineering Society, IES, "rated life" like  $B_{50}$  at 10.000 hours, means that at least 50% of the units will survive 10.000 hours of life.*
- \* *Some examples:*

	Life time [Hours]	MTBF [hours]	Comments
Driver 1	50.000		$T_{\text{case max}} = 80^{\circ}\text{C}$ , $T_{\text{ambient max}} = 50^{\circ}\text{C}$
Driver 2	79.000	484.000	80% load, $T_{\text{ambient}} = 45^{\circ}\text{C}$
Driver 3	50.000		Typical 116.000 hours
Driver 4	120.000	600.000	Life at 80% load, $T_{\text{case}} = 60^{\circ}\text{C}$ , $T_{\text{case max}} = 75^{\circ}\text{C}$ , MTBF at $25^{\circ}\text{C}$

# High Temperatures critical - Temp cycling may be worse!



- *Many electronics drivers come with fine lifetime estimations – but sometimes reality is cruel:*
  - *In one project almost 50% of all lamps (several thousands) failed within 3 -4 years after installation*

# Potting of electronics



- \* *Potting of electronics is normally considered a good approach (better mechanical protection, better humidity resistance, with correct filler use also better temperature distribution, etc.*
- \* *But potting can also create problems !*



# IP rating chart



- \* *Ingress protection (IP) tell users the environmental protection that a driver's outer casing provides.*

1 <sup>st</sup> Digit	Solid Object Protection	2 <sup>nd</sup> Digit	Water Protection
0	Not protected	0	Not Protected
1	Protected against solid objects greater than 50mm (e.g. accidental bump of hand)	1	Protected against vertically dripping water
2	Protected against solid objects greater than 12.5mm (e.g. fingers)	2	Protected against sprays of water when tilted up to 15 degrees vertically
3	Protected against solid objects greater than 2.5mm (e.g. tools and wires wires)	3	Protected against sprays of water when tilted up to 60 degrees vertically
4	Protected against solid objects greater than 1mm (e.g. small wires)	4	Protected against water sprayed in all directions
5	Protected against dust	5	Protected against low-pressure jetting water from all directions
6	Dust tight (total protection)	6	Protected against powerfully jetting water from all directions
<p>IP 6 7 Code Letters 1st Digit 2nd Digit</p>		7	Protected against temporary immersion in water (under 30 minutes)
		8	Protected against continuous immersion in water

# Potting



- \* *Thermal cycling applications:*
  - *A high Tg indicates that the adhesive will perform well as temperatures rise, while flexibility allows the adhesive to absorb thermally- induced stresses and resist cold-temperature brittleness.*
  
- \* *Challenges*
  - *Wear/abrasion*
  - *Cracking*
  - *Loss of adhesion*
  - *Bubbles*
  - *Blistering*
  - *Charring*
  - *Degradation*
  - *Lack of sufficient fillers*
  - *Chemical attack*



# Temp cycling may cause mechanical tension!



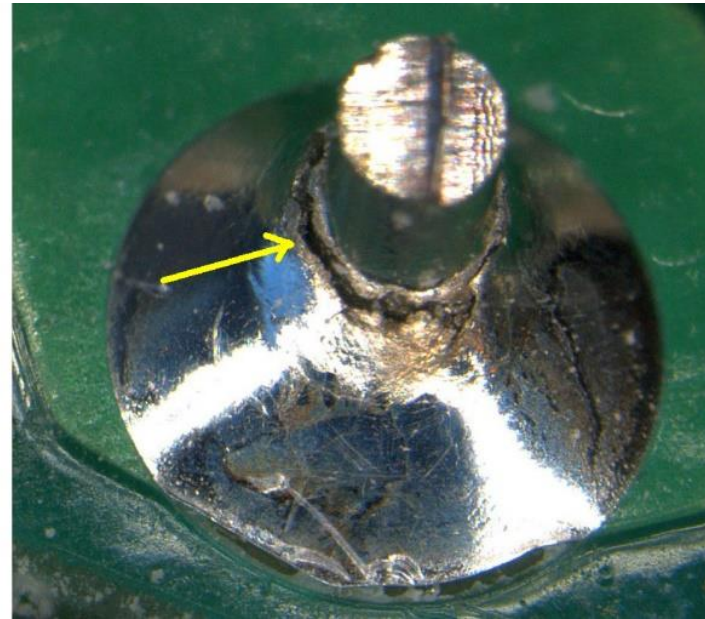
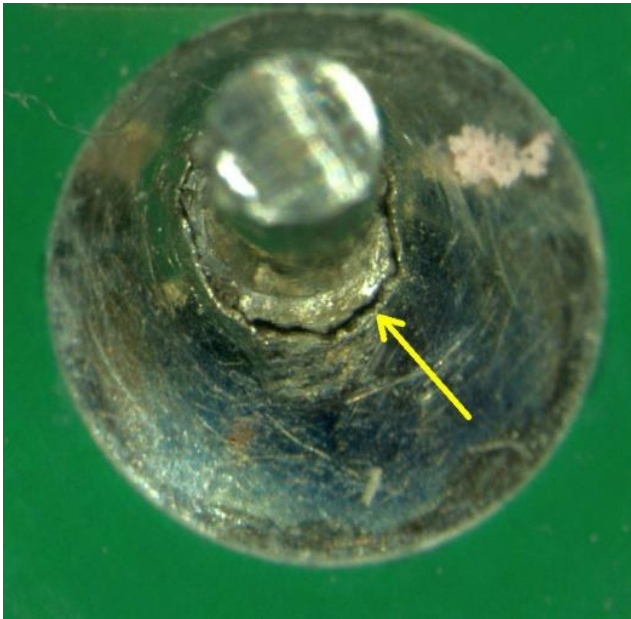
- \* *Temperature cycling can prove a much more difficult challenge than high temperature.*
- \* *E.g. on a cold winter day, the ambient temperature may change from  $-10^{\circ}\text{C}$  to  $+50^{\circ}\text{C}$ , TC point temperature even more.*



# Soldering broken



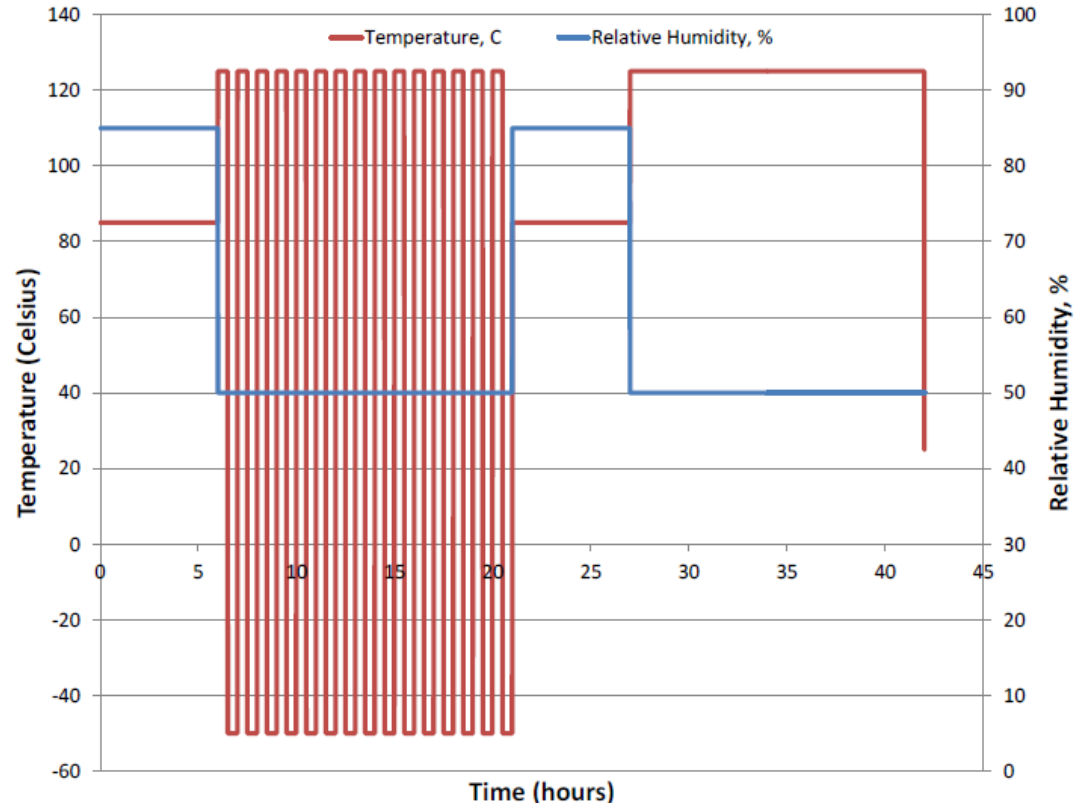
- \* *Axial leads on large components are under extensive mechanical tension during temperature cycling.*



# The "Hammer" test for luminaires (accelerated life testing)



- \* *Stage 1: Steady-state temperature humidity biased life test consisting of 6 hours at 85°C and 85% relative humidity (RH).*
- \* *Stage 2: Temperature shock consisting of 15 hours cycling at –50°C to +125°C (air-to-air). Hold time at each extreme was 30 minutes.*
- \* *Stage 3: Steady-state temperature humidity biased life test consisting of 6 hours at 85°C and 85% RH.*
- \* *Stage 4: High-temperature operational lifetime consisting of 15 hours at 120°C.*

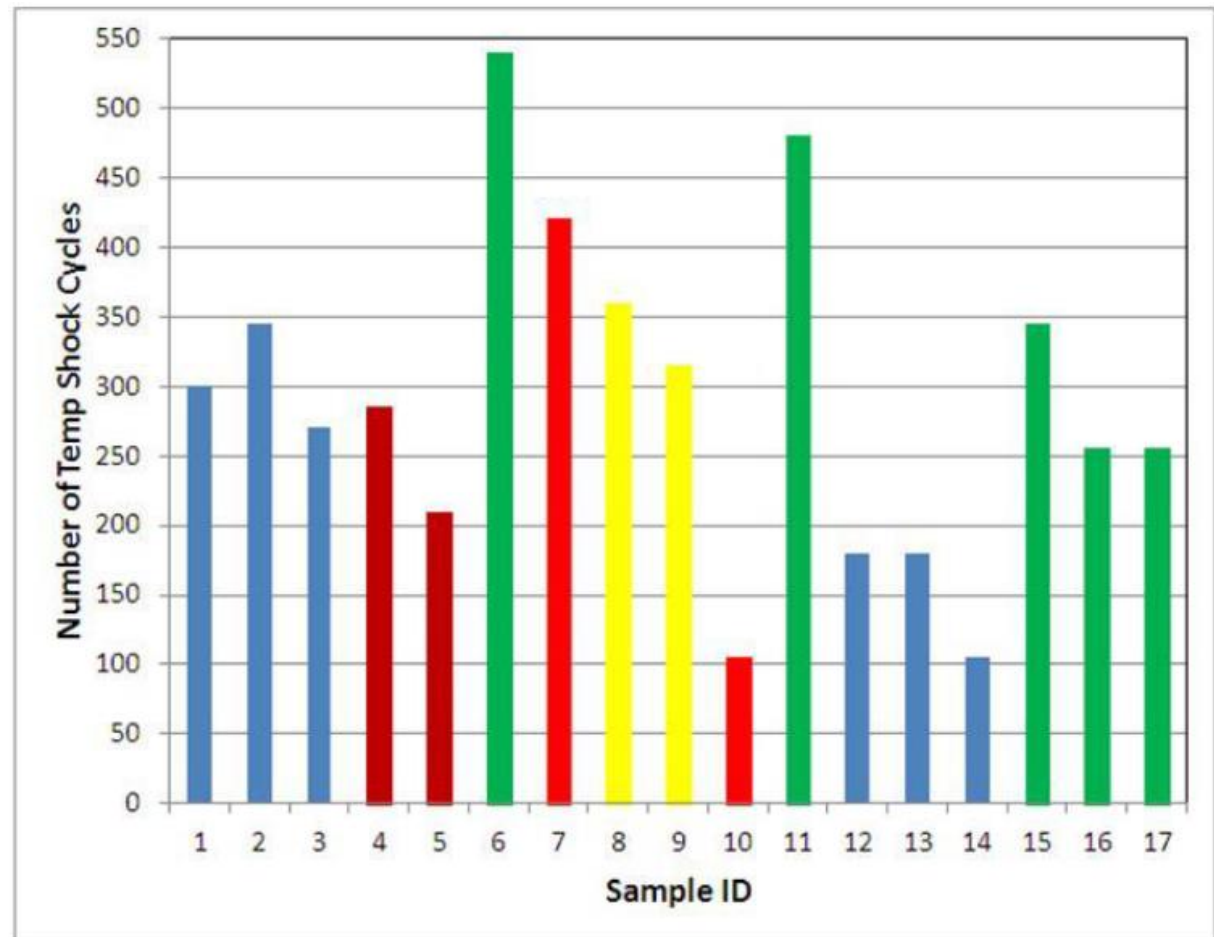


Source: Hammer Testing Findings for Solid-State Lighting Luminaires  
"US Department of Energy

# "Hammer test" results



- \* Hammer test performed on luminaires for in-door applications.
- \* Code:
  - Blue: PCB failure
  - Dark red: Capacitor
  - Light red: Other components.
  - Yellow: Solder interconnects
  - Green: Still operating.





# Critical Components

# Components that may prove critical

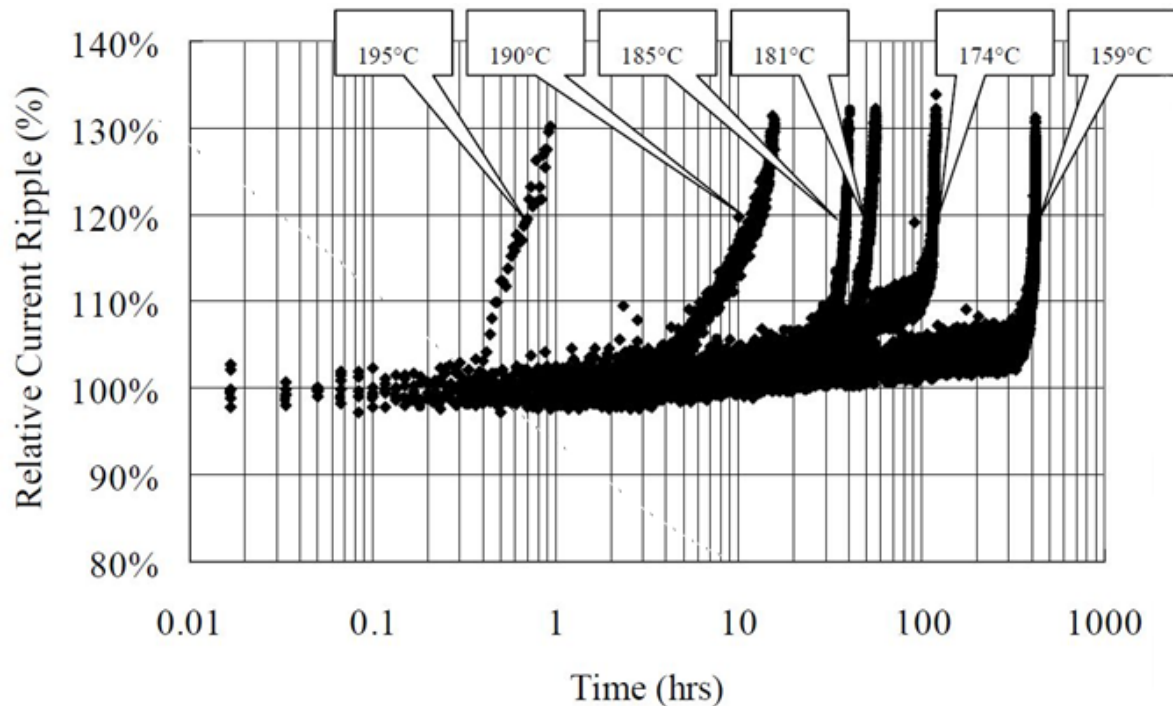


- \* *Electrolytic capacitors*
- \* *Varistors*
- \* *Microelectronics*
- \* *Others*

# Critical components in electronic drivers



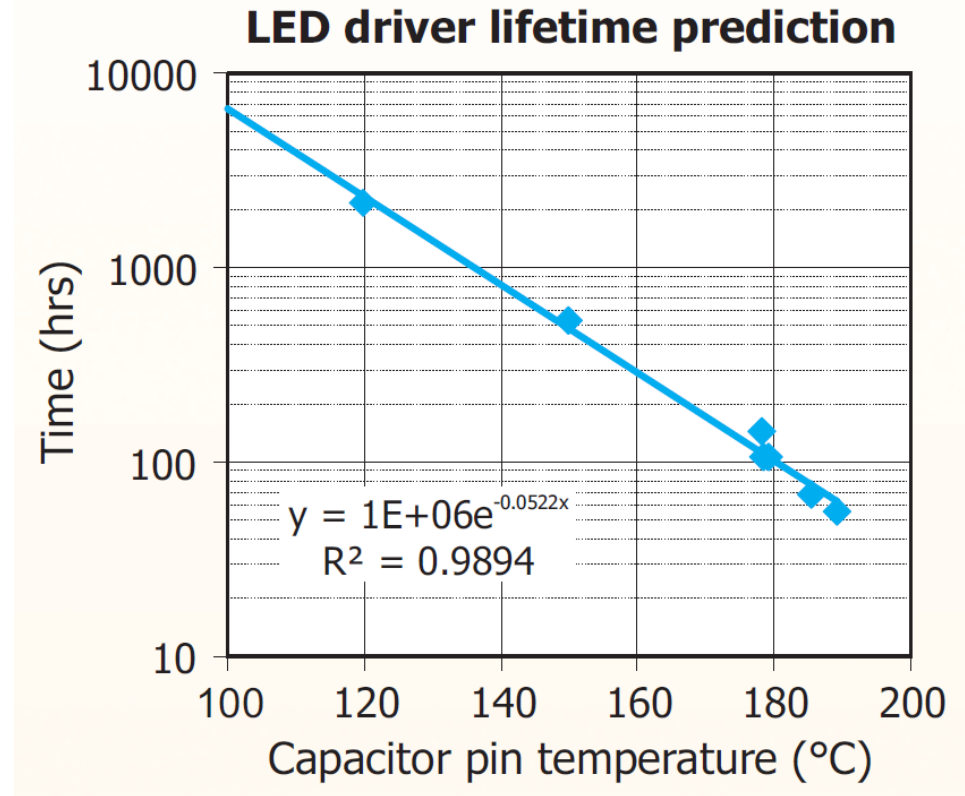
- \* *Electrolytic capacitors are frequent causes of errors in electronic drivers*



# The electrolytic capacitor – a critical component



- \* Experiments have shown that electrolytic capacitors are typical the most sensitive electronic component in term of reliability.
- \* In the example (right):  
 $T_A = 85^\circ\text{C}$  and  $T_{PIN} = 100^\circ\text{C}$ .  
Estimated lifetime approx. 7.000 hours.
- \* For every  $10^\circ\text{C}$  increase in temperature, the life time typically decreases by 50%.
- \* Electrolytic capacitors come in many classifications.
  - Look for long-life electrolytic capacitors

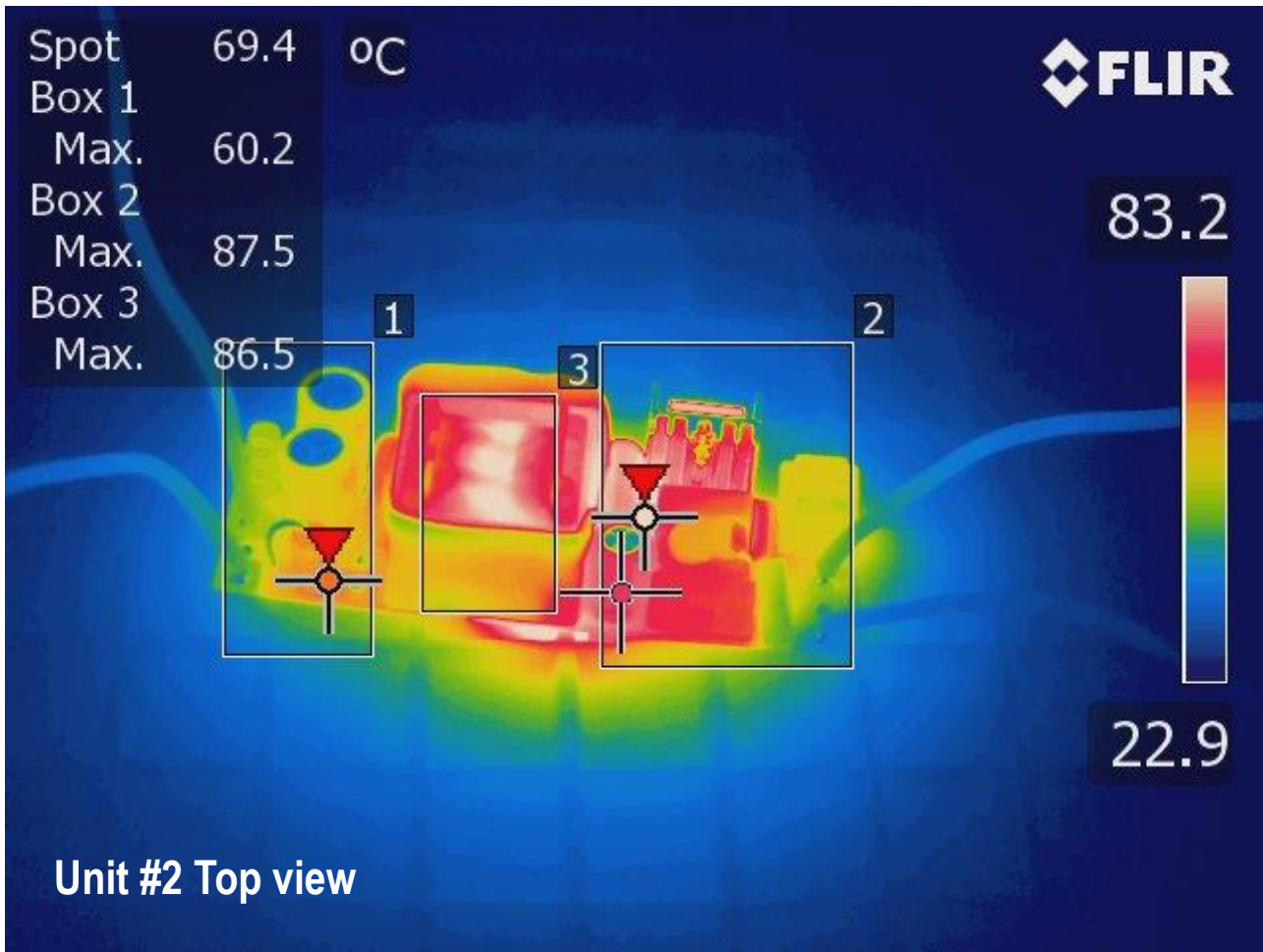


Source: Lighting Research Center  
Rensselaer Polytechnic Institute, USA





- *Other components such as varistors, microelectronics, etc. may also be limiting factors of a design.*
- *At TestForum 2015 in Oslo, I showed some examples of critical microelectronic parts in driver design.*

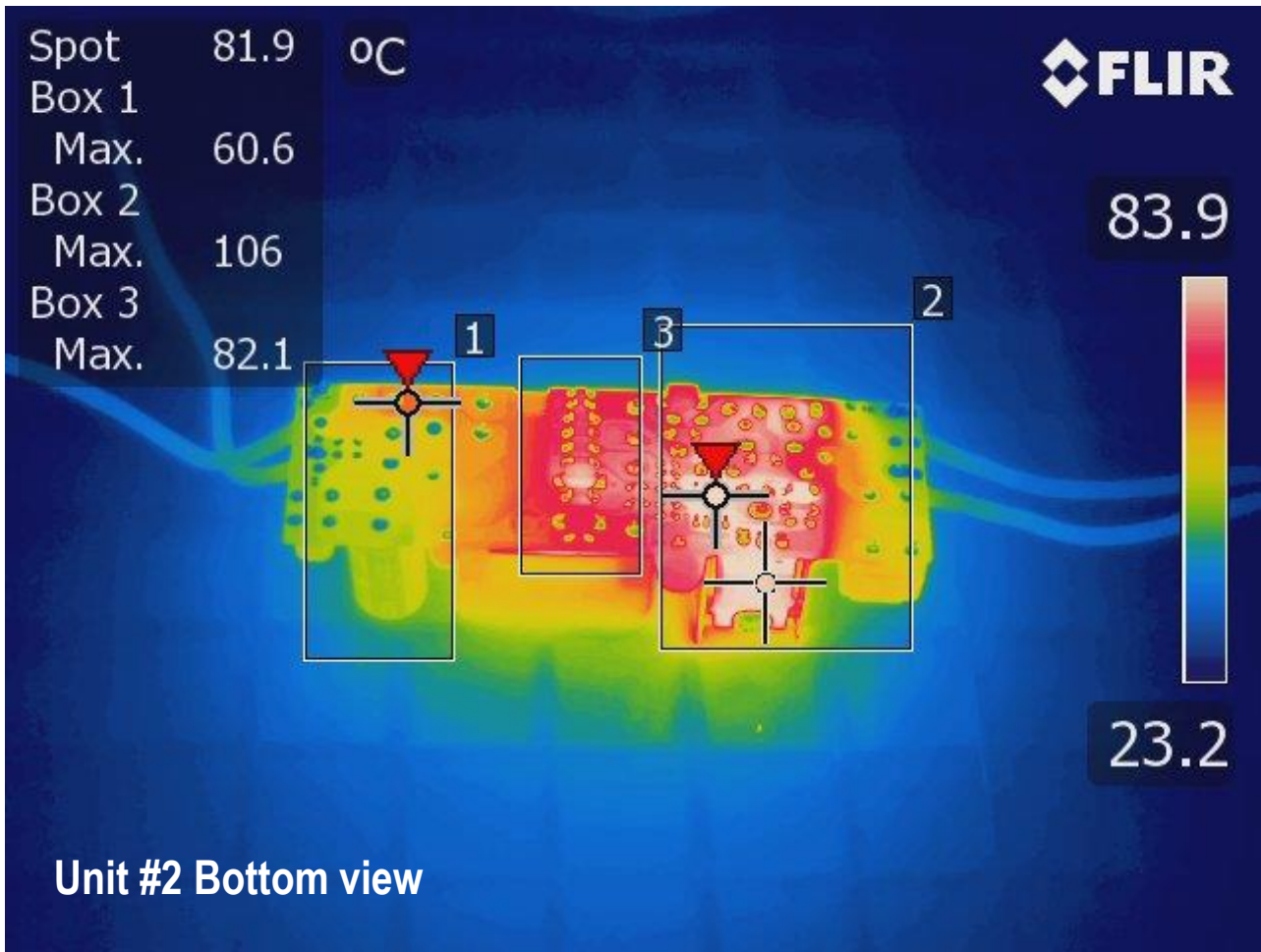


Shenzhen Qihan Power Co.,Ltd.

230V AC

QH-40W10-18x3W							
Vac	Vout	Iout	Pin	Pout	Efficiency	Max T1	MaxT2
100 VAC	58	0,493	37	28,6	77%	87,5 diode bridge	Transformer 84
230 VAC	58	0,543	39,3	33,75	80%	87,5 Transformer	84 PCB
100 VAC B						80 snubber diode	74 Power IC
230 VAC B						106 IC?	82 snubber diode/PowerMOSFET

Source:  
DTU Electro



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Source:  
DTU Electro



# Electrical environment (transients)

# Electrical application environments

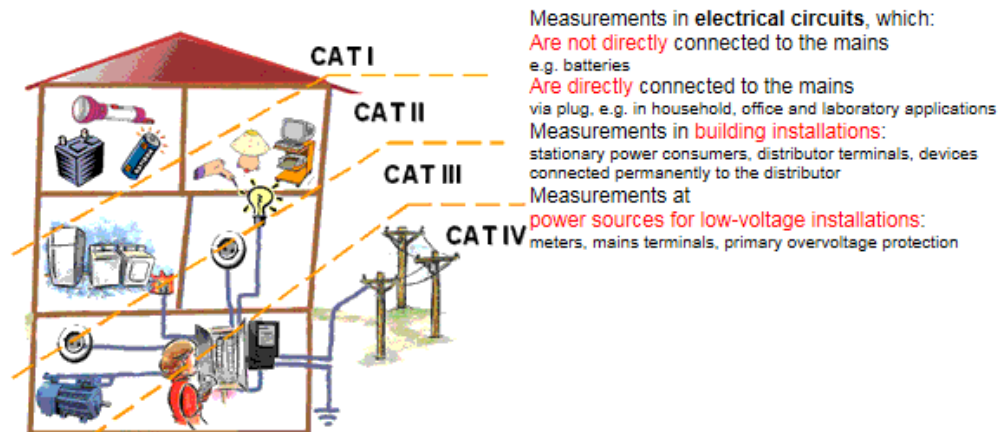


- \* *Electrical applications environments have different challenges whether for use in building applications or use in e.g. rough outdoor applications.*

Level	Open-circuit test voltage	
	Line-to-line	Line-to-ground
1	-	0,5 kV
2	0,5 kV	1 kV
3	1 kV	2 kV
4	2 kV	4 kV
X	Special	Special

## Measuring Category

The following measuring categories have been established by the EN 61010-1 standard.

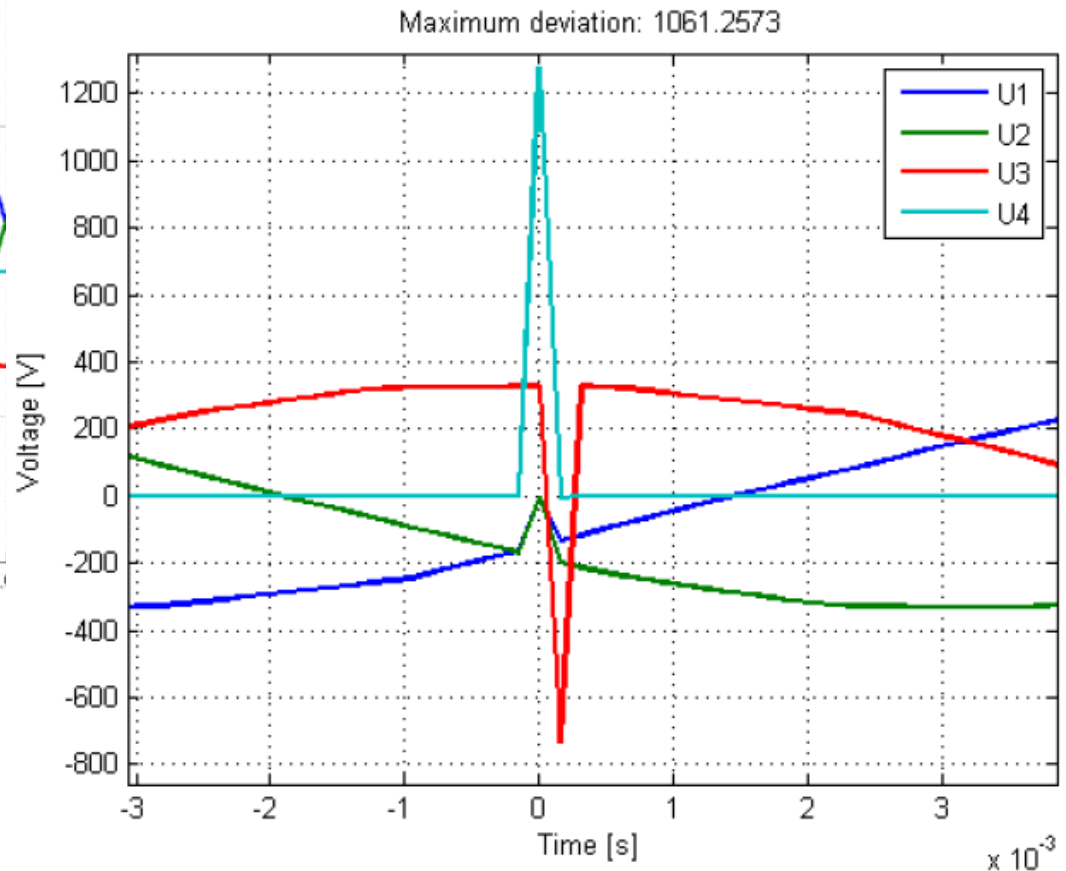
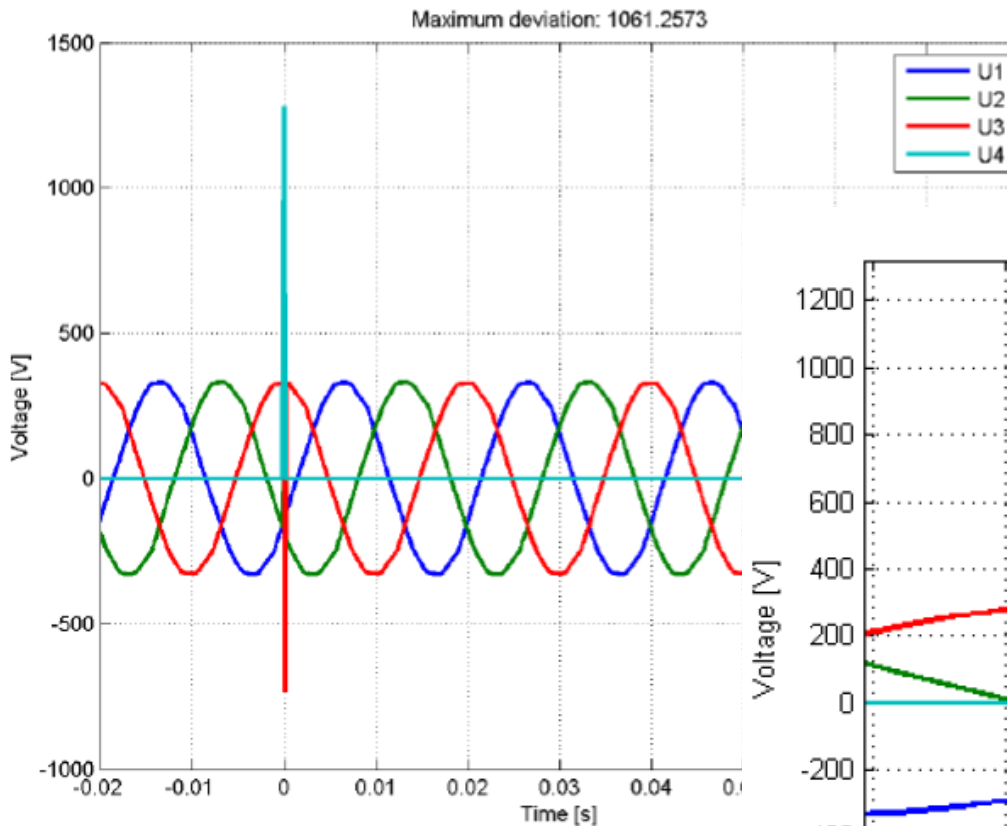


Transients, resulting for example from lightning strikes or load switching, become greater and more energetic as the distance from the point of measurement to the power source for the low-voltage system decreases.



IEC 61000-4-5:2014  
Test conditions

# Transients: Few millisec or less

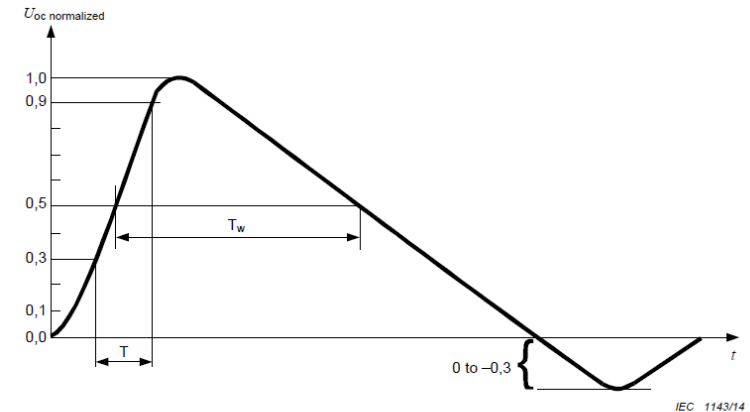


# Power Quality – Denmark



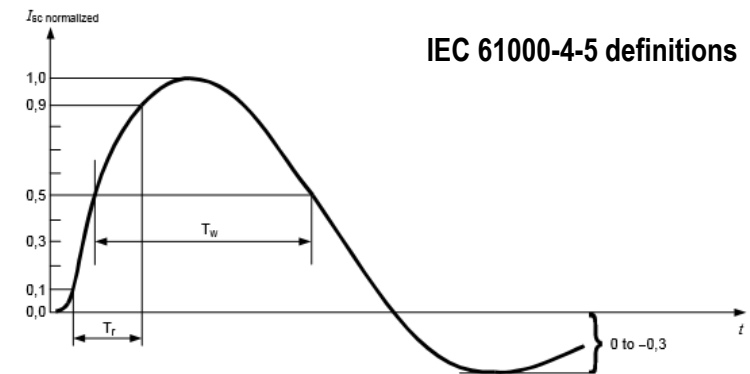
- \* *Denmark: high quality power grid.*
- \* *Basically all power through cables.*
- \* *Systematic recordings sin 2009*
- \* *Approx. 70 years of accumulated recording time (22 recorders in use)*
- \* *Thousands of transients recorded:*
  - *>23.000 events of >100V instantaneous deviations from nominal 230V*
  - *>3.500 events of >200V from nominal 230V*
  - *Transients up to 7,5kV<sub>peak</sub> observed*

## Open circuit voltage



Front time:  $T_f = 1,67 \times T = 1,2 \mu\text{s} \pm 30 \%$   
Duration:  $T_d = T_w = 50 \mu\text{s} \pm 20 \%$

## Short circuit current



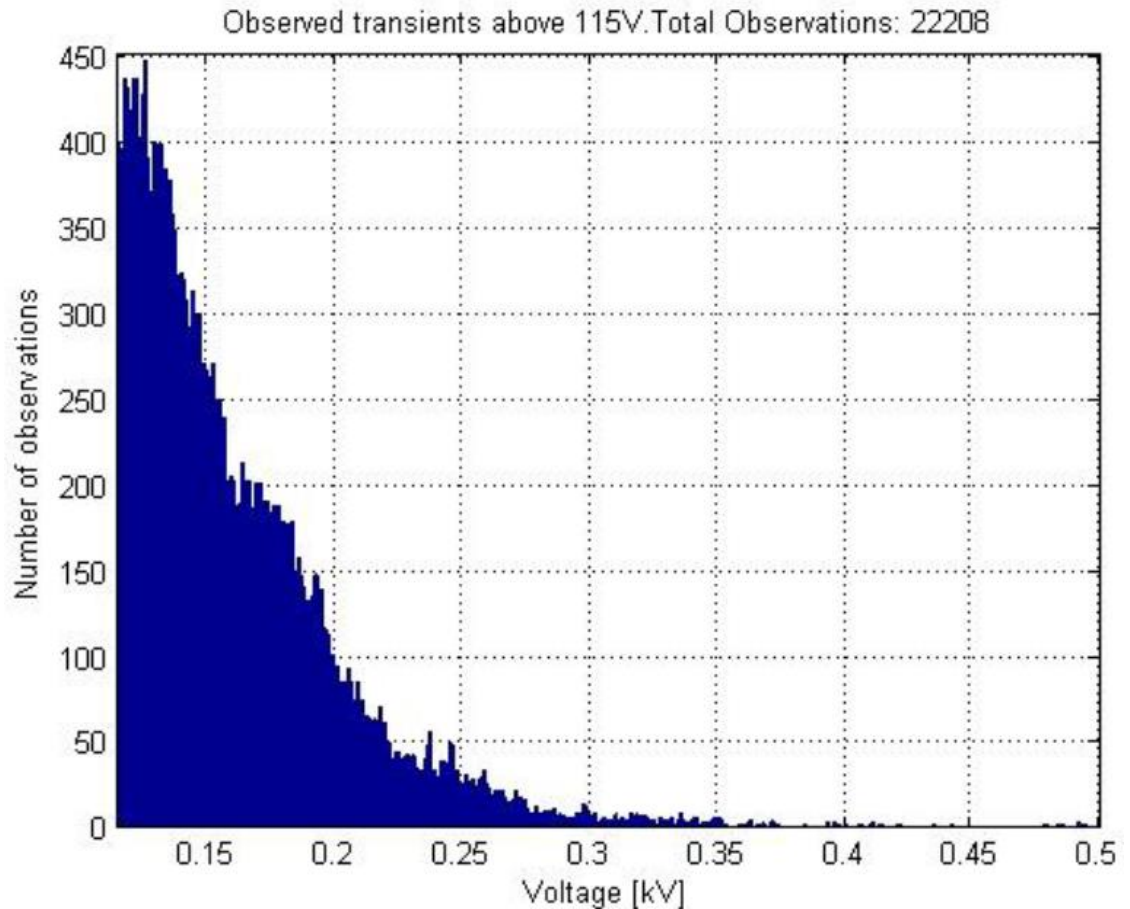
IEC 61000-4-5 definitions

Front time:  $T_f = 1,25 \times T_r = 8 \mu\text{s} \pm 20 \%$   
Duration:  $T_d = 1,18 \times T_w = 20 \mu\text{s} \pm 20 \%$

# Power Quality – Denmark



- \* 22.208 transients  
 $115V < U < 500V$
- \* Majority of transients  
 $< 300V_{peak}$
- \* Many transients  
within  $\pm 315 V$  range
- \* Probability:  
1 every 27,6 minutes



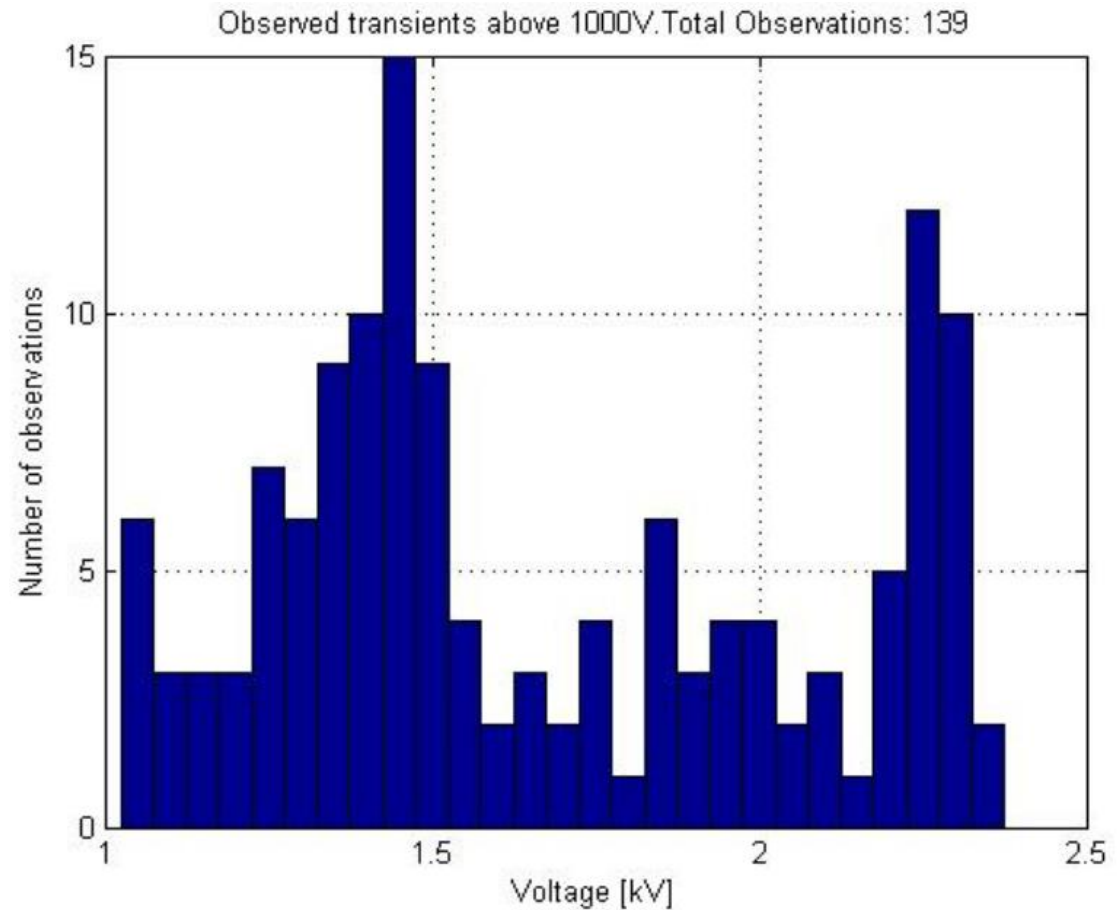
Source: Dansk Energi



# Power Quality – Denmark



- \* 139 transients  
 $1\text{kV} < U < 2,5\text{kV}$
- \* Transients between  
 $1\text{kV}$  and  $2,5\text{kV}$  are  
rare
- \* Probability:  
1 every  $\frac{1}{2}$ y year

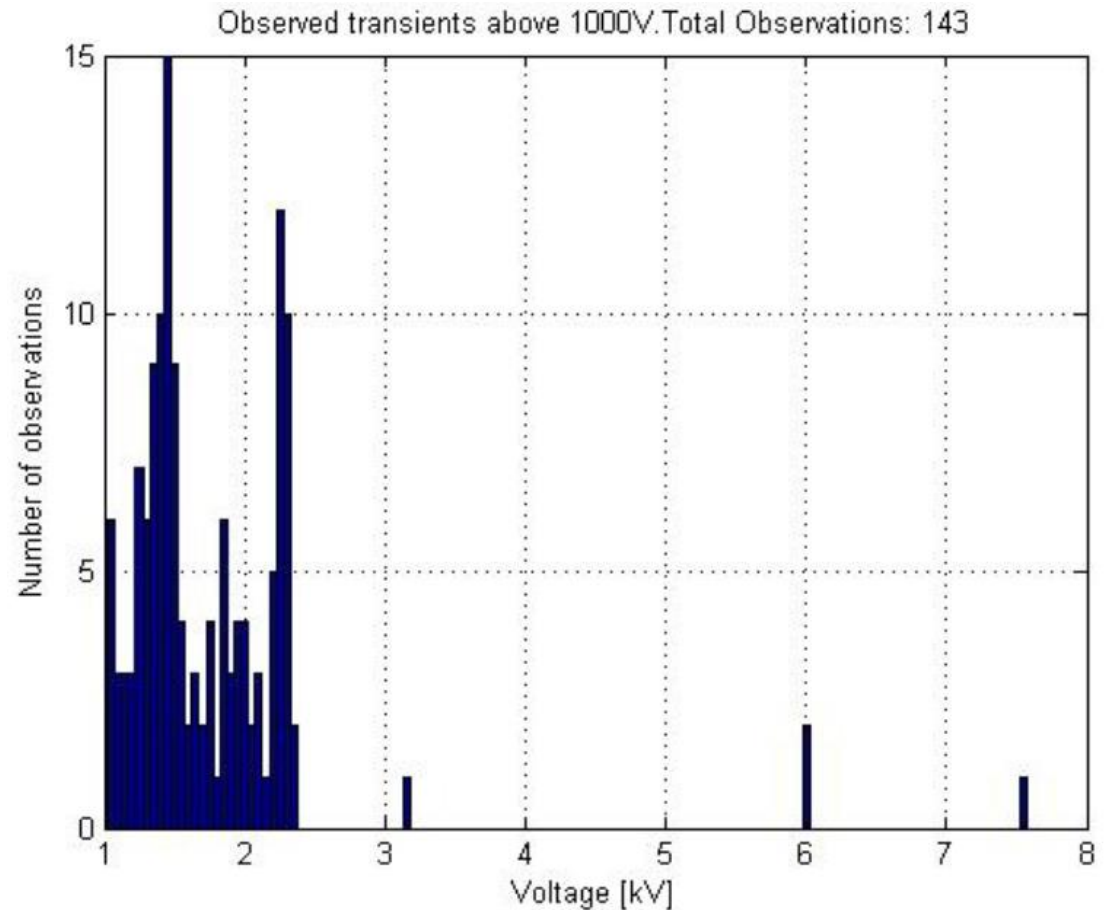


Source: Dansk Energi

# Power Quality – Denmark



- \* Only few transients above 2,5 kV are observed
- \* Probability:  
4 transients above 2,5 kV observed in a total of 70 accumulated measurement years (= 1 in every 18 recorded years)

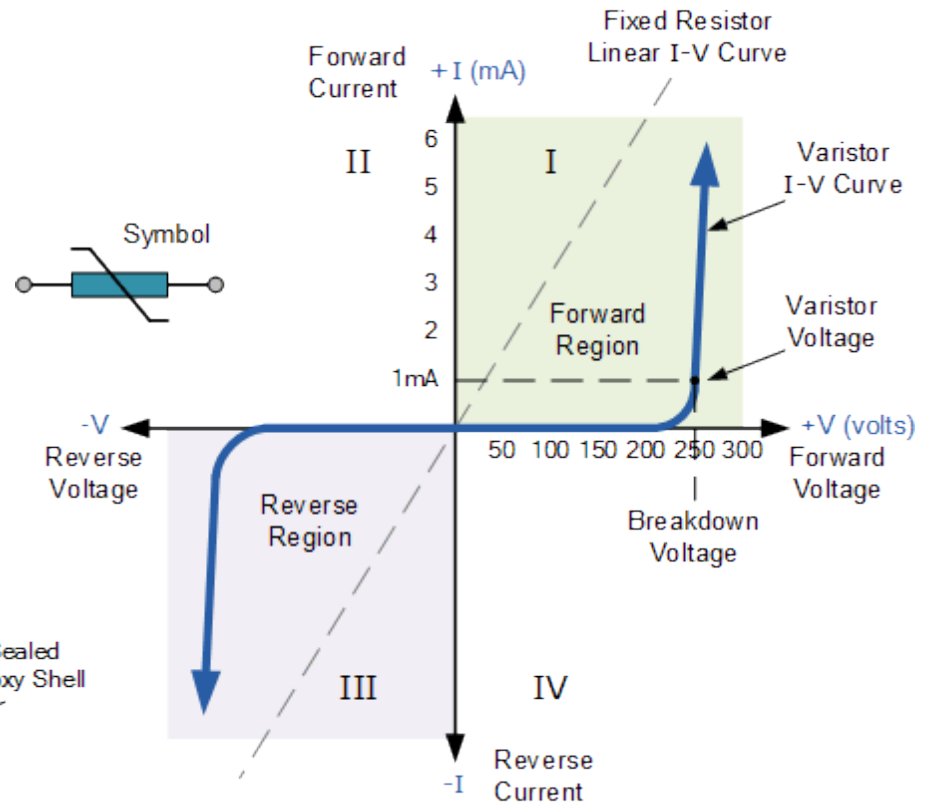
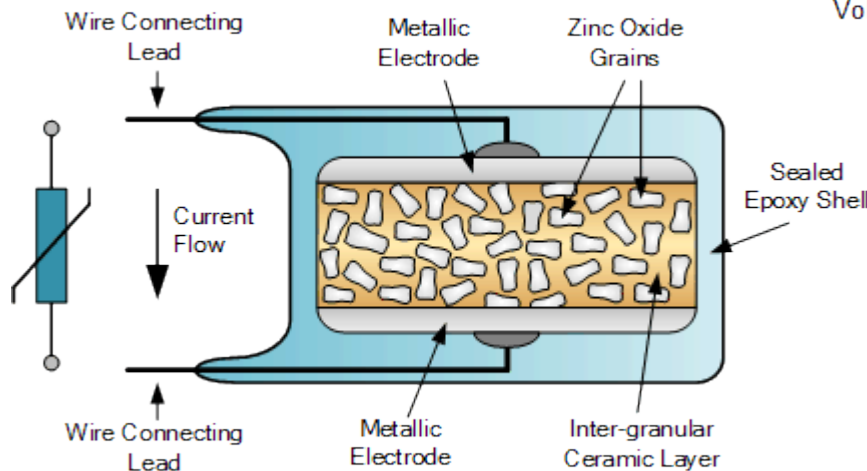


Source: Dansk Energi

# Varistors



- \* Varistor = **VARI**label resi**STOR**
- \* Has bidirectional characteristics making it suitable for protection.
- \* Usually based on metal-oxide technology



# Electrical overstress



- \* *Electrical overstress damages components, here:*
  - *Microelectronics*
  - *Varistor*

